Search Notes					

Application/Control No.	ontrol No. Applicant(s)/Patent under Reexamination	
10/763,981	VIGH, GYULA	
Examiner	Art Unit	
Surekha Vathyam	1753	

SEARCHED					
Class	Subclass	Date	Examiner		
204	548, 644	8/29/2007	sv		
204	450-470	8/29/2007	SV		
204	600-621	8/29/2007	sv		
updated		7-10-2008	кко		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	1.				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
see attached EAST search history	8/29/2007	sv		
Inventor nam esearch on EAST and Google Scholar	8/29/2007	sv		
Searched Google Scholar keywords IEF auxiliary pH bias	8/29/2007	sv		
Consulted Alex Noguerola for search	8/29/2007	sv		